

L Number	Hits	Search Text	DB	Time stamp
-	4198	324/750-753,537,765-766.ccls.	USPAT; US-PGPUB	2004/10/07 13:41
-	243	324/750-753,537,765-766.ccls. and secondary adj electron	USPAT; US-PGPUB	2004/10/05 18:48
-	74	(324/750-753,537,765-766.ccls. and secondary adj electron) and reflected	USPAT; US-PGPUB	2004/10/05 18:49
-	24	((324/750-753,537,765-766.ccls. and secondary adj electron) and reflected) and board	USPAT; US-PGPUB	2004/10/05 19:15
-	0	((324/750-753,537,765-766.ccls. and secondary adj electron) and reflected) and shrinkage	USPAT; US-PGPUB	2004/10/05 18:51
-	24	((324/750-753,537,765-766.ccls. and secondary adj electron) and reflected) and (shrinkage REDUCTION)	USPAT; US-PGPUB	2004/10/05 19:14
-	3	((324/750-753,537,765-766.ccls. and secondary adj electron) and reflected) and board and primary adj electron with (shrinkage REDU\$5)	USPAT; US-PGPUB	2004/10/05 19:15
-	726	250/\$.ccls. and primary adj beam	USPAT; US-PGPUB	2004/10/06 14:21
-	108	250/\$.ccls. and primary adj beam and secondary adj beam	USPAT; US-PGPUB	2004/10/06 14:21
-	28	250/\$.ccls. and (primary adj beam and secondary adj beam).clm.	USPAT; US-PGPUB	2004/10/06 14:33
-	8	250/\$.ccls. and (control\$5 same primary adj beam and secondary adj beam).clm.	USPAT; US-PGPUB	2004/10/06 16:07
-	21	250/\$.ccls. and primary adj beam and secondary adj beam and (damage shrinkage)	USPAT; US-PGPUB	2004/10/06 16:31
-	0	primary adj beam and secondary adj beam and (damage with shrinkage)	USPAT; US-PGPUB	2004/10/06 16:31
-	0	primary adj beam and secondary adj beam and (damage same shrinkage)	USPAT; US-PGPUB	2004/10/06 16:31
-	2	primary adj beam and secondary adj beam and shrinkage	USPAT; US-PGPUB	2004/10/06 16:32
-	218	electron adj beam and shrinkage with pattern	USPAT; US-PGPUB	2004/10/06 16:32
-	25	electron adj beam same shrinkage with pattern	USPAT; US-PGPUB	2004/10/06 16:33
-	11	electron adj beam with shrinkage with pattern	USPAT; US-PGPUB	2004/10/06 16:33
-	3427	250/306-307,310-311.ccls.	USPAT; US-PGPUB	2004/10/06 18:05
-	0	(250/306-307,310-311.ccls. and shrinkage with pattern) and ev	USPAT; US-PGPUB	2004/10/06 18:12
-	8	250/306-307,310-311.ccls. and shrinkage with pattern	USPAT; US-PGPUB	2004/10/06 18:10
-	7	(250/306-307,310-311.ccls. and shrinkage with pattern) and kv	USPAT; US-PGPUB	2004/10/06 18:15
-	0	((250/306-307,310-311.ccls. and shrinkage with pattern) and kv) and low adj permittivity	USPAT; US-PGPUB	2004/10/06 18:16
-	0	((250/306-307,310-311.ccls. and shrinkage with pattern) and kv) and porous	USPAT; US-PGPUB	2004/10/06 18:16
-	0	((250/306-307,310-311.ccls. and shrinkage with pattern) and kv) and resin	USPAT; US-PGPUB	2004/10/06 18:19
-	0	((250/306-307,310-311.ccls. and shrinkage with pattern) and kv) and xlk adj film	USPAT; US-PGPUB	2004/10/06 18:18
-	7	((250/306-307,310-311.ccls. and shrinkage with pattern) and kv) and resist	USPAT; US-PGPUB	2004/10/06 18:22
-	0	resist with porous with low adj permittivity	USPAT; US-PGPUB	2004/10/06 18:24
-	1122	resist with porous	USPAT; US-PGPUB	2004/10/06 18:22
-	8	resist adj porous	USPAT; US-PGPUB	2004/10/06 18:22
-	1	resist adj low adj permittivity	USPAT; US-PGPUB	2004/10/06 18:32

-	18	resist with low adj permittivity	USPAT; US-PGPUB	2004/10/06 18:30
-	120	hydrogensilsesquioxane	USPAT; US-PGPUB	2004/10/06 18:30
-	2	hydrogensilsesquioxane with resist	USPAT; US-PGPUB	2004/10/06 18:31